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## **MTT-S Booth #544**

Photo available at [http://www.jmicrotechnology.com/PRPictsFolder/NAT\\_31.jpg](http://www.jmicrotechnology.com/PRPictsFolder/NAT_31.jpg)

Data sheet available at: [http://www.jmicrotechnology.com/NAT-31\\_DataSheet.pdf](http://www.jmicrotechnology.com/NAT-31_DataSheet.pdf)

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### **J microTechnology's NAT-31 42X-540X Microscope Inspection System for Microprobing Resolves 1 Micron or Less Features**

**Portland, OR –June 4, 2007** – J microTechnology, Inc., specialists in electrical and mechanical test products for advanced semiconductor and packaged devices, introduces the NAT-31 42X-540X Microscope Inspection System with Universal Serial Bus (USB) 2.0 Camera. Based on high clarity zoom optics and an USB 2.0 digital camera, it resolves 1 micron or less features when added to a J microTechnology probe station, thus providing a cost-effective, versatile solution for clinical, life science, materials science, semiconductor, and educational professionals, especially those in demanding research environments and teaching facilities.

The NAT-31 System zoom optics have a 0.7X-4.5X objective lens providing magnification of 42X- 270X for probe placement and device under test (DUT) alignment with the standard 0.5X auxiliary lens. Removal of the auxiliary lens changes the range of magnification to 84X-540X for inspection and fine geometry probing. It comes with a 2X relay lens and a 0.5X or 1.0X(no lens) objective multiplier. There is a long working distance of 108mm (4.25") for the 540X optics and 189mm (7.4") for the 270X option. The extremely long working distance allows for flexibility with fixtures.

With 1280x1024 resolution and on-board video processing in the camera, the system delivers outstanding image quality. Live video preview provides for real-time focus. Auto exposure and

“auto white balance” efficiently capture the optimal image. An intuitive user application provides camera controls, while full integration to popular third-party imaging applications is available through TWAIN drivers. The TWAIN interface results in rapid image capture, archiving and documentation, still and video. The camera provides a progressive scan of 1.3 megapixels, with 30-bit color depth and RGB capture, all seen in a full color preview window on the PC.

The USB 2.0 digital interface ensures a simple plug and play installation. One standard cable minimizes camera wiring clutter. No additional hardware frame grabber is required. The software is compatible with Windows 2000 and Windows XP. Optional relay lens are available.

The NAT-31 System, when combined with J microTechnology’s probe stations, can be used to zoom in to find and inspect defects or abnormalities on wafers or devices in the semiconductor industry, or on substrates or other materials used in clinical or scientific laboratories and research facilities. Its flexibility and relatively low cost make it a valuable tool to the educational community.

“This product was requested by our university customers who wanted to be able to use our probe stations and needed both normal probe placement magnification and high power magnification, but didn’t want the expense of a short working distance optical viewing microscope,” said Louis Schappacher, applications specialist for J microTechnology.

Prices for the NAT-31 are about \$7000.00. Pricing can vary due to order configuration and shipping destination. Delivery is about 3 weeks aro.

### **About J microTechnology**

J microTechnology, Inc. is dedicated to the supply and distribution of accessory products for the electrical and mechanical test of advanced semiconductor and packaged devices. The products supply a comprehensive set of accessories for precision testing and microprobing of non-coplanar structures. Primary products include microprobing fixtures, probe stations, custom and standard ProbePoint™ product thin film adapter interface circuits, calibration standards substrates, and high performance laboratory test cables and are also compatible with microfluidic probes. Customers include systems integrators, semiconductor and semiconductor package manufacturers, and government and university laboratories worldwide for use in transistor (FET, PHEMT, etc.) characterization, multichip MIC/MMIC assembly production test point, electro-optic device test adapters, MEMS, nanoelectronics devices, biomedical sensors, and high

performance and low cost package characterization. Started in 1992, J microTechnology is based in Portland, Oregon. For more information visit [www.jmicrotechnology.com](http://www.jmicrotechnology.com).

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